

STP36N55M5 STW36N55M5

N-channel 550 V, 0.06 Ωtyp., 33 A MDmesh™ V Power MOSFET in TO-220 and TO-247 packages

Datasheet — production data

Features

Order codes	V _{DSS} @ T _{Jmax}	R _{DS(on)} max	I _D
STP36N55M5	600 V	< 0.08 Ω	33 A
STW36N55M5	000 V	< 0.00 32	33 A

- Worldwide best R_{DS(on)} * area
- Higher V_{DSS} rating and high dv/dt capability
- Excellent switching performance
- 100% avalanche tested

Applications

Switching applications

Description

These devices are N-channel MDmesh™ V Power MOSFETs based on an innovative proprietary vertical process technology, which is combined with STMicroelectronics' well-known PowerMESH™ horizontal layout structure. The resulting product has extremely low onresistance, which is unmatched among siliconbased Power MOSFETs, making it especially suitable for applications which require superior power density and outstanding efficiency.

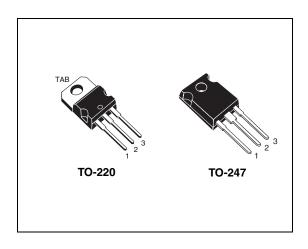


Figure 1. Internal schematic diagram

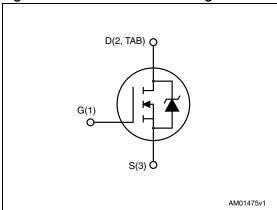


Table 1. Device summary

Order codes	Marking	Package	Packaging
STP36N55M5	36N55M5	TO-220	Tube
STW36N55M5	CIVICENIOC	TO-247	iube

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1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{GS}	Gate-source voltage	± 25	٧
I _D	Drain current (continuous) at T _C = 25 °C	33	Α
I _D	Drain current (continuous) at T _C = 100 °C	20.8	Α
I _{DM} ⁽¹⁾	Drain current (pulsed)	132	Α
P _{TOT}	Total dissipation at T _C = 25 °C	190	W
dv/dt (1)	Peak diode recovery voltage slope	15	V/ns
T _{stg}	Storage temperature	- 55 to 150	°C
Tj	Max. operating junction temperature	150	°C

^{1.} $I_{SD} \le 33 \text{ A, di/dt } \le 400 \text{ A/}\mu\text{s; } V_{DS(Peak)} < V_{(BR)DSS}, V_{DD} = 340 \text{ V.}$

Table 3. Thermal data

Symbol	Parameter	Va	lue	Unit
Symbol	raiametei	TO-220	TO-247	Onne
R _{thj-case}	Thermal resistance junction-case max	0.66		°C/W
R _{thj-amb}	Thermal resistance junction-ambient max	62.5 50		°C/W

Table 4. Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AR}	Avalanche current, repetetive or not repetetive (pulse width limited by T_{jmax})	7	Α
E _{AS}	Single pulse avalanche energy (starting T_J =25°C, I_D = I_{AR} ; V_{DD} =50 V)	510	mJ

2 Electrical characteristics

(T_C = 25 °C unless otherwise specified)

Table 5. On /off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 1 mA, V _{GS} = 0	550			٧
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = 550 V V _{DS} = 550 V, T _C =125 °C			1 100	μ Α μ Α
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 25 V			± 100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3	4	5	٧
R _{DS(on)}	Static drain-source on-resistance	V _{GS} = 10 V, I _D = 16.5 A		0.06	0.08	Ω

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 100 \text{ V, f} = 1 \text{ MHz,}$ $V_{GS} = 0$	-	2670 75 6.6	-	pF pF pF
C _{o(tr)} ⁽¹⁾	Equivalent capacitance time related	$V_{DS} = 0$ to 440 V, $V_{GS} = 0$	•	192	-	pF
C _{o(er)} ⁽²⁾	Equivalent capacitance energy related	V _{DS} = 0 to 440 v, v _{GS} = 0	-	71	-	pF
R _G	Intrinsic gate resistance	f = 1 MHz open drain	-	1.85	-	Ω
Qg	Total gate charge	V _{DD} = 440 V, I _D = 16.5 A,		62		nC
Q_{gs}	Gate-source charge	V _{GS} = 10 V	-	15	-	nC
Q_{gd}	Gate-drain charge	(see Figure 18)		27		nC

^{1.} Time related is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

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^{2.} Energy related is defined as a constant equivalent capacitance giving the same stored energy as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
t _{d(V)}	Voltage delay time	V _{DD} = 400 V, I _D = 22 A,		56		ns
t _{r(V)}	Voltage rise time	$R_G = 4.7 \Omega$, $V_{GS} = 10 V$		13		ns
t _{f(i)}	Current fall time	(see <i>Figure 19</i> and	-	13	_	ns
t _{c(off)}	Crossing time	Figure 22)		17		ns

Table 8. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current Source-drain current (pulsed)		-		33 132	A A
V _{SD} (2)	Forward on voltage	I _{SD} = 33 A, V _{GS} = 0	-		1.5	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} = 33 A, di/dt = 100 A/μs V _{DD} = 100 V (see <i>Figure 22</i>)	-	334 5 31		ns μC A
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 33$ A, di/dt = 100 A/ μ s $V_{DD} = 100$ V, $T_j = 150$ °C (see <i>Figure 22</i>)	-	406 7 35		ns μC A

^{1.} Pulse width limited by safe operating area.

^{2.} Pulsed: pulse duration = 300 μ s, duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for TO-220 Fig

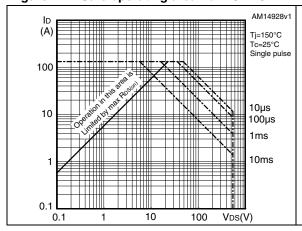


Figure 3. Thermal impedance for TO-220

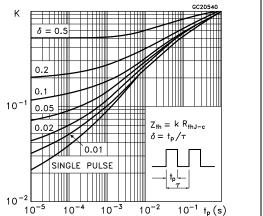


Figure 4. Safe operating area for TO-247

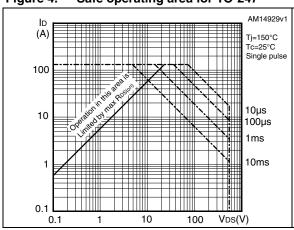


Figure 5. Thermal impedance for TO-247

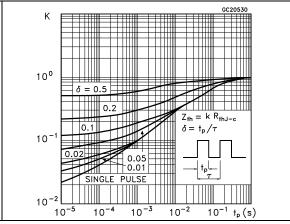


Figure 6. Output characteristics

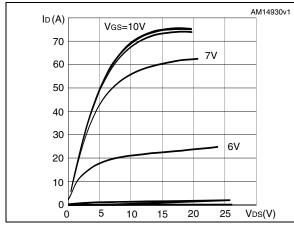
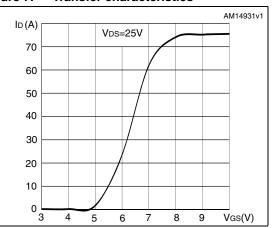


Figure 7. Transfer characteristics



AM14932v1 AM14933v1 Vgs RDS(on) V_{DS}(V) $(\dot{\Omega})$ (V) Vgs=10V VDS VDD=440V 450 12 ID=16.5A 400 0.065 10 350 0.06 300 8 250 6 0.055 200 150 100 0.05 50 0.045 10 20 30 40 50 60 70 Qg(nC) 5 10 15 20 25 30 ID(A)

Figure 8. Gate charge vs gate-source voltage Figure 9. Static drain-source on-resistance

Figure 10. Capacitance variations

Figure 11. Output capacitance stored energy

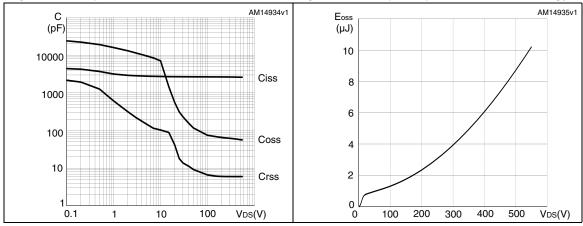


Figure 12. Normalized gate threshold voltage Figure 13. Normalized on-resistance vs vs temperature temperature

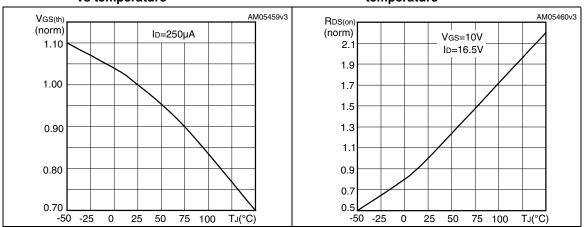
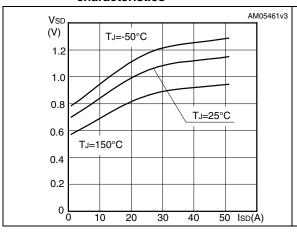


Figure 14. Source-drain diode forward characteristics

Figure 15. Normalized B_{VDSS} vs temperature



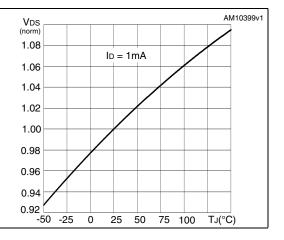
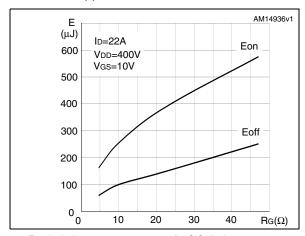


Figure 16. Switching losses vs gate resistance (1)



1. Eon including reverse recovery of a SiC diode

3 Test circuits

Figure 17. Switching times test circuit for resistive load

Figure 18. Gate charge test circuit

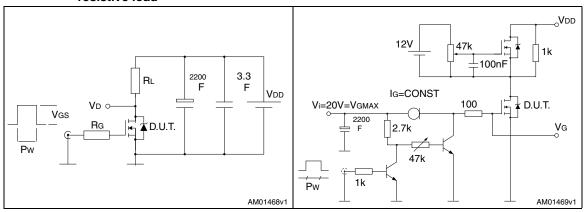


Figure 19. Test circuit for inductive load switching and diode recovery times

Figure 20. Unclamped inductive load test circuit

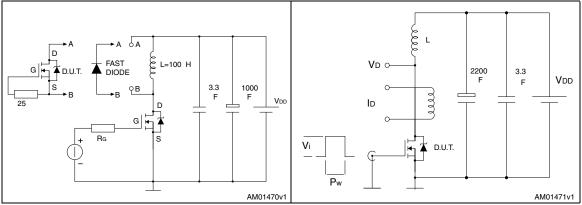
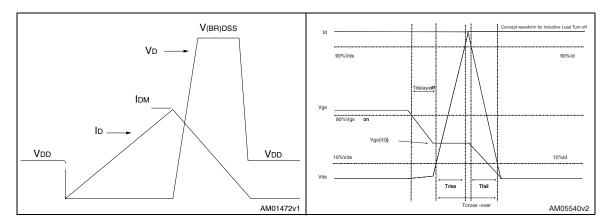


Figure 21. Unclamped inductive waveform

Figure 22. Switching time waveform



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4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

Table 9. TO-220 type A mechanical data

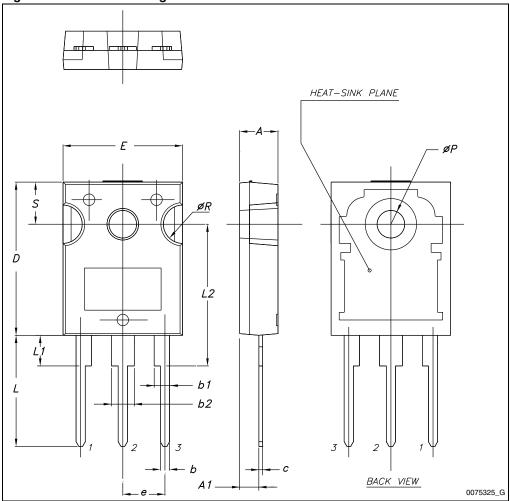
Dim		mm	
Dim.	Min.	Тур.	Max.
А	4.40		4.60
b	0.61		0.88
b1	1.14		1.70
С	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10		10.40
е	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13		14
L1	3.50		3.93
L20		16.40	
L30		28.90	
ØP	3.75		3.85
Q	2.65		2.95

Figure 23. TO-220 type A drawing

Table 10. TO-247 mechanical data

Dim.		mm.	
Dilli.	Min.	Тур.	Max.
А	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
С	0.40		0.80
D	19.85		20.15
E	15.45		15.75
е	5.30	5.45	5.60
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
ØP	3.55		3.65
ØR	4.50		5.50
S	5.30	5.50	5.70

Figure 24. TO-247 drawing



5 Revision history

Table 11. Document revision history

Date	Revision	Changes
07-Mar-2012	1	First release.
23-Oct-2012	2	Document status promoted from preliminary data to production data.

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